



Declaration of Conformity



Type of equipment: 3M CS Mount Lens (DC-IRIS)
Brand Name /Trade Mark: SAMSUNG
Type designation /model: SLA-M2890DN
Applicant: SAMSUNG TECHWIN CO., LTD.

In accordance with the following Directives:

2004/108/EC The Electromagnetic Compatibility Directive
Including amendments by the CE Marking Directive 93/68/EEC

2011/65/EU Restriction of the use of certain hazardous substances in electrical and electronic equipment (recast)

The following harmonized European standards or technical specifications have been applied:

EN 55022:2010	Limits and methods of measurement of radio disturbance characteristics of information technology equipment
EN 50581:2012	Technical documentation for the assessment of electrical and electronic products with respect to the restriction of hazardous substances
EN 50130-4:2011	Product family standard: Immunity requirements for components of fire, intruder and social alarm systems
EN 61000-4-2:2009	Electrostatic discharge immunity test
EN 61000-4-3:2006+A2:2010	Radiated, radio-frequency, electromagnetic field immunity test

The CE Marking on the products and/or their packaging signifies that SAMSUNG TECHWIN CO., LTD. holds the reference technical file available to the European Union authorities.

Place and date of issue: 84, Jeongdong-ro, Seongsan-gu, Changwon-si, Gyeongsangnam-do, Korea / June 11, 2014

Authorized Signatory: Name : Jei Soon, Kang
Title : Principal Research Engineer
Signature :

EMC TEST REPORT

Test report No : EMC-CE-4943
Type of Equipment : 3M CS Mount Lens (DC-IRIS)
Model Name : SLA-M2890DN
Applicant : Samsung Techwin Co., Ltd.
84, Jeongdong-ro, Seongsan-gu, Changwon-si,
Gyeongsangnam-do, Korea
Manufacturer #1 : Samsung Techwin Co., Ltd.
84, Jeongdong-ro, Seongsan-gu, Changwon-si,
Gyeongsangnam-do, Korea
Manufacturer #2 : TIANJIN SAMSUNG TECHWIN
OPTO-ELECTRONIC CO., LTD
No.11 Weiliu Road. Micro-Electronic Industrial
Park Jingang Road Tianjin 300385, China
Test standards : EN 55022:2010, Class A
EN 50130-4:2011
Testing Laboratory : EMC Compliance Ltd.
Test result : Complied

This product complies with the requirements of the EMC Directive 2004/108/ EC.

The results in this report apply only to the sample tested.

This test report shall not be reproduced, except in full, without the written approval of EMC compliance Laboratory.

Date of receipt: 2014. 05. 26

Date of testing: 2014. 06. 05 ~ 06. 09

Issued date: 2014. 06. 11

Tested by:

JUNG, YOUNG-JUN

Approved by:

YEOM, HAN-SEOK

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1. Applicant information

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Manufacturer#2: TIANJIN SAMSUNG TECHWIN OPTO-ELECTRONIC CO., LTD
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2. Laboratory information

Address

EMC compliance Ltd.

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Telephone Number: 82 31 336 9919

Facsimile Number: 82 505 299 8311

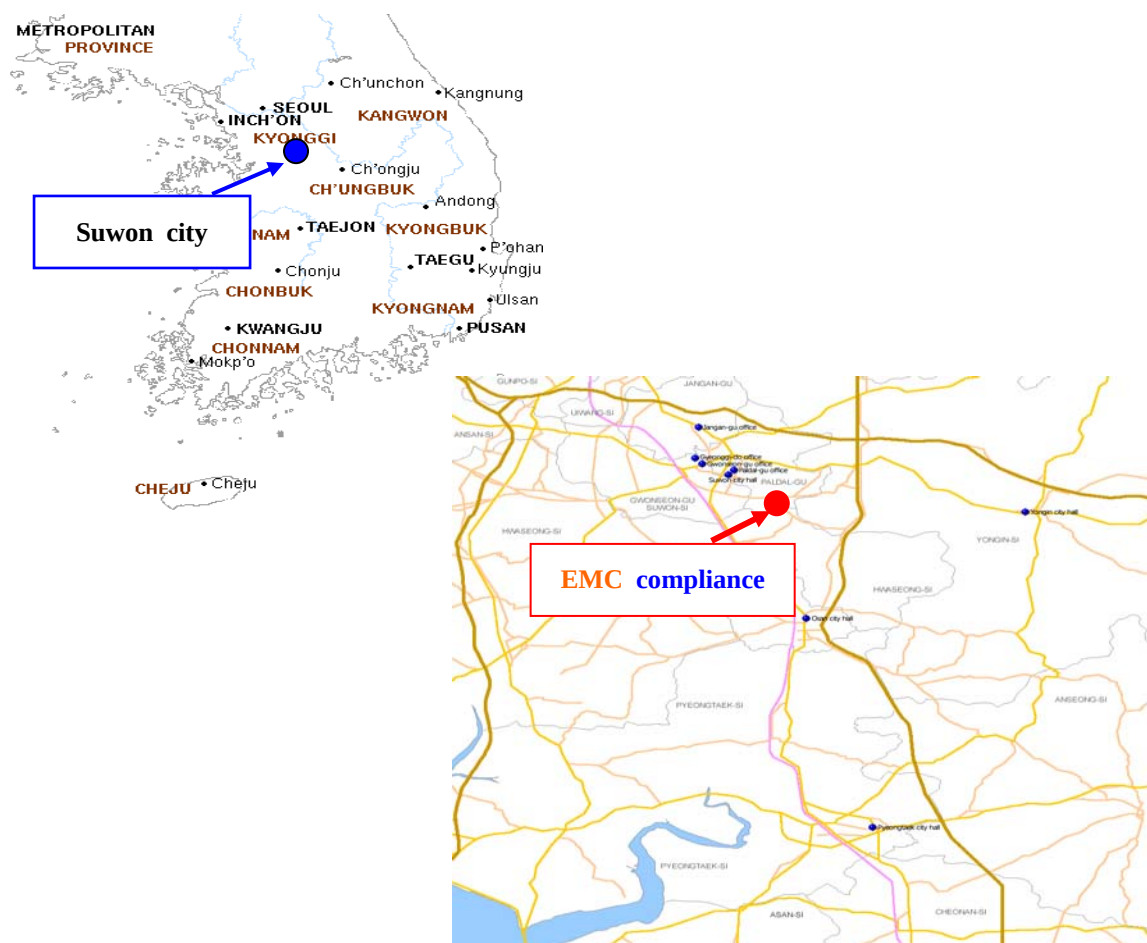
FCC CAB.: KR0040

VCCI Registration No. : R-3327, G-198, C-3706, T-1849

Industry Canada Registration No. : 8035A

KOLAS NO.: 231

SITE MAP



3. Test system configuration

3.1 Operation environment

	Temperature	Humidity	Pressure
Chamber(10 m)	: 24.3 °C	51.3 % R.H.	-
Shielded room(ESD)	: 22.6 °C	46.9 % R.H.	100.2 kPa

Test site

These testing items were performed following locations;

Test item	Test site
Conducted Emission	Shielded Room
Radiated Emission	10 m Chamber
Harmonics current	Immunity area
Voltage fluctuations and flickers	Immunity area
Electrostatic discharge	Shielded Room
Radiated RF immunity	Fully anechoic chamber (3 m)
Electric Fast Transient/BURST	Shielded Room
Surge	Shielded Room
Conducted RF immunity	Shielded Room
Voltage dip/interruption	Shielded Room
Mains supply voltage variations	Shielded Room

3.2 Measurement Uncertainty

All measurements involve certain levels of uncertainties, especially in field of EMC.

The factors contributing to uncertainties are test receiver, cable loss, antenna factor calibration, Antenna directivity, antenna factor variation with height, antenna phase center variation, antenna frequency interpolation, measurement distance variation, site imperfection, mismatch, and system repeatability. Based on CISPR 16-4-2, the measurement uncertainty level with a 95 % confidence level was applied.

Conducted emission measurement (C.L: Approx 95 %, k = 2)		
Shielded Room (CE#1)	9 kHz ~ 150 kHz: ± 3.82 dB 150 kHz ~ 30 MHz: ± 3.43 dB	
Shielded Room (CE#2)	9 kHz ~ 150 kHz: ± 3.82 dB 150 kHz ~ 30 MHz: ± 3.43 dB	
Shielded Room (CE#3)	9 kHz ~ 150 kHz: ± 4.00 dB 150 kHz ~ 30 MHz: ± 3.63 dB	
Radiated Emission measurement (C.L: Approx 95 %, k = 2)		
10 m Chamber (#F4)	30 MHz ~ 300 MHz	3 m: + 4.56 dB, - 4.58 dB 10 m: + 4.56 dB, - 4.56 dB
	300 MHz ~ 1 000 MHz	3 m: + 4.84 dB, - 4.85 dB 10 m: + 4.71 dB, - 4.72 dB
	1 GHz ~ 6 GHz	3 m: + 6.19 dB, - 6.20 dB
10 m Chamber (#F2)	30 MHz ~ 300 MHz	3 m: + 4.86 dB, - 4.88 dB 10 m: + 4.86 dB, - 4.86 dB
	300 MHz ~ 1 000 MHz	3 m: + 4.98 dB, - 4.99 dB 10 m: + 4.85 dB, - 4.87 dB
	1 GHz ~ 6 GHz	3 m: + 6.19 dB, - 6.20 dB
Radio Frequency Electromagnetic Fields (C.L: Approx 95 %, k = 2)		
± 1.82 dB		
Disturbance power Electromagnetic Fields (C.L: Approx 95 %, k = 2)		
± 3.73 dB		

4. Description of E.U.T.

4.1 General information

Product Name		 SLA-M2890DN 	SLA-M2890PN
Image			
CCD Size		1/2.8" (Diagonal 6.49mm)	1/2.8" (Diagonal 6.49mm)
해상도 Resolution		3 Megapixel	3 Megapixel
Zoom Ratio		3.2x	3.2x
Focal Length		2.8 ~ 9mm	2.8 ~ 9mm
Max. Aperture Ratio		1:1.2	1:1.2
Max. Image Format		5.12mm x 3.84mm (Max Ø6.7)	5.12mm x 3.84mm (Max Ø6.7)
Angle of View	Diagonal	134.2° ~ 42.7°	134.2° ~ 42.7°
	Horizontal	104.2° ~ 33.7°	104.2° ~ 33.7°
	Vertical	77.2° ~ 25.3°	77.24° ~ 25.3°
Operation	Iris	DC Auto Iris(F1.2 ~ F360C)	P-Iris(F1.2 ~ F360C)
	Focus	Manual(0.3m ~ ∞)	Manual(0.3m ~ ∞)
	Zoom	Manual(2.8 ~ 9mm)	Manual(2.8 ~ 9mm)
Iris Type		DC Iris	P-Iris
Back Focal Length		7.52mm(In Air)	7.5mm(In Air)
Flange Back Length		12.5mm	12.5mm
Mount		CS-mount	CS-mount
Operating Temperature		-10°C ~ +50°C (+14°F ~ +122°F)	-10°C ~ +50°C (+14°F ~ +122°F)
Dimensions(wxhxd)		40 x 51.5 x 63mm (1.57" x 2.03" x 2.48")	40 x 51.5 x 63mm (1.57" x 2.03" x 2.48")
Weight		84g (0.19lb)	82.1g (0.18lb)

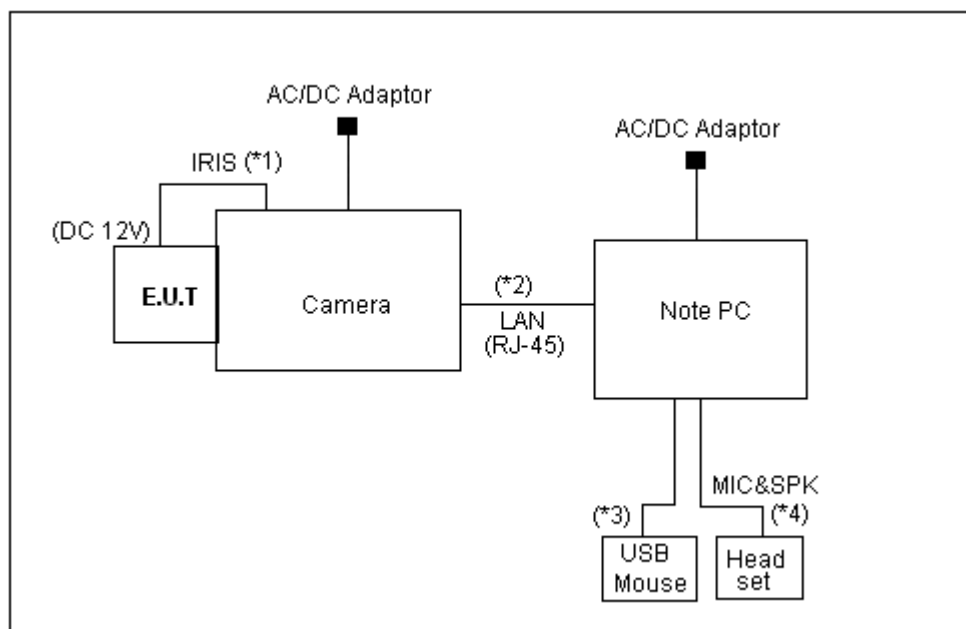
4.2 Product description

Type of product	3M CS Mount Lens (DC-IRIS)
Model name (Basic)	SLA-M2890DN
Model name (Variant)	-
Difference	-
Trade name	-
Serial no	Engineering Sample
Testing voltage	DC 12 V
Product rating	DC 12 V
Internal clock frequency	Above 108 MHz
Note	-

4.3 Auxiliary equipments

Type	Model / Part #	Serial number	Manufacturer
Note PC	-	-	HP
Camera	SNB-6004N		Samsung Techwin
USB Mouse	1088	8165906051248	Microsoft
Headset	SHS-250V	-	SAMSUNG
AC/DC Adaptor	DSA-42D-12	-	-

4.4 Test configuration



Note	Start		End		Cable		
	Name	I/O port	Name	I/O port	Length (m)	Spec.	Cable
1	EUT (3M CS Mount Lens (DC-IRIS))	IRIS	Camera	IRIS	0.1	Non-Shield	-
2	Note PC	LAN(RJ-45)	Camera	LAN(RJ-45)	3.0	Non-Shield	-
3		USB	USB Mouse	USB	1.8	Shield	-
4		MIC&SPK	Headset	MIC&SPK	2.0	Non-Shield	-

4.5 Operating conditions

The EUT was configured as normal intended use.

Test mode	Normal operating
1	Web viewer test.

5. Summary of test results

5.1 Summary of EMI emission test results

Applied	Test items	Test method	Result
☐	Conducted Emission	EN 55022:2010	N/A
☒	Radiated Emission	EN 55022:2010	Complied
☐	Harmonics current	EN 61000-3-2:2006+A1:2009+A2:2009	N/A
☐	Voltage fluctuations and flickers	EN 61000-3-3:2008	N/A

5.2 Summary of immunity test results

Applied	Test items	Test method	Result
* EN 50130-4:2011			
☒	Electrostatic discharge	EN 61000-4-2:2009	Complied
☒	Radiated RF immunity	EN 61000-4-3:2006+A2:2010	Complied
☐	Electric Fast Transient/BURST	EN 61000-4-4: 2012	N/A
☐	Surge	EN 61000-4-5:2006	N/A
☐	Conducted RF immunity	EN 61000-4-6:2009	N/A
☐	Voltage dip/interruption	EN 61000-4-11:2004	N/A
☐	Mains supply voltage variations	EN 50130-4:2011	N/A

5.3 Performance criteria

The variety and the diversity of the apparatus within the scope of this document makes it difficult to define precise criteria for the evaluation of the immunity test results.

If as a result of the application of the tests defined in this standard, the apparatus becomes dangerous or unsafe then the apparatus shall be deemed to have failed the test.

A functional description and a definition of performance by the manufacture and noted in the test report, based on the following criteria:

Electrostatic discharge

There shall be no damage, malfunction or change of status due to the conditioning.

Flickering of an indicator during the application of discharge is permissible, providing which could be interpreted by associated equipment as a change,

Radiated electromagnetic fields

There shall be no damage, malfunction or change of status due to the conditioning.

Flickering of an indicator during the application of discharge is permissible, providing which could be interpreted by associated equipment as a change, and no such

Flickering of indicators occurs at a field strength of 3 V/m. For components of CCTV systems, where the picture is allowed at 10 V/m, providing.

- (a) there is no permanent damage or change to EUT
(e.g. no corruption of memory or changes to programmable setting etc.)
- (b) at 3 V/m, any deterioration of the picture is so minor that the system could still be used; and
- (c) there is no observable deterioration of the picture at 1 V/m.

Fast transient burst / slow high energy voltage surge

There shall be no damage, malfunction or change of status due to the conditioning.

Flickering of an indicator during the application of discharge is permissible, providing

That there is no residual is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as

Conducted RF immunity

There shall be no damage, malfunction or change of status due to the conditioning.

Flickering of an indicator during the application of discharge is permissible, providing

That there is no residual is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change, and no such flickering of indicators occurs at $U = 130 \text{ dB}\mu\text{V}$.

For component of CCTV systems, where the status is monitored by observing the TV picture, then deterioration of the picture is allowed at $U = 140 \text{ dB}\mu\text{V}$, providing:

- (a) there is no permanent damage or change to the EUT
(e.g. no corruption of memory or changes to programmable settings etc.)
- (b) at $U = 130 \text{ dB}\mu\text{V}$, any deterioration of the picture is so minor that the system could still be used; and
- (c) there is no observable deterioration of the picture at $U = 120 \text{ dB}\mu\text{V}$.

Voltage dip/interruption / Voltage variation

There shall be no damage, malfunction or change of status due to the conditioning.

Flickering of an indicator during the conditioning is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change. The EUT shall meet the acceptance criteria for the functional test, after the conditioning.

6. Test results

6.1 Radiated Emission

Test specification	EN 55022:2010, Class A		
Testing voltage	DC 12 V		
Test facility	10 m Chamber (#F2)		
Test distance	10 m, 3 m		
Date	2014. 06. 09		
Temperature (°C)	24.3 °C	Humidity (% R.H.)	51.3 % R.H.
Remarks	Complied		

6.1.1 Limits of radiated emission measurement

☒ Limits below 1 GHz

Frequency [MHz]	Class A (dB(μV/m)) @ 10 m	Class B (dB(μV/m)) @ 10 m
30 ~ 230	40	30
230 ~ 1 000	47	37

☒ Limits above 1 GHz

Frequency [GHz]	Class A @ 3 m		Class B @ 3 m	
	Average limit (dB(μV/m))	Peak limit (dB(μV/m))	Average limit (dB(μV/m))	Peak limit (dB(μV/m))
1 ~ 3	56	76	50	70
3 ~ 6	60	80	54	74

Note - The lower limit applies at the transition frequency.

6.1.2 Measurement procedure

The test was done at a 10 m chamber with a quasi-peak detector. EUT was placed on a non-metallic table height of 0.8 m above the reference ground plane. Cables were folded back and forth forming a bundle 0.3 m to 0.4 m long and were hanged at a 0.4 m height to the ground plane.

Cables connected to EUT were fixed to cause maximum emission. Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength.

6.1.3 Used equipments

Equipment	Model no.	Serial no.	Makers	Next Cal. Date	Used
Test Receiver	ESCI7	100732	R&S	2015.01.27	☐
Test Receiver	ESCI	100001	R&S	2014.07.25	☐
Test Receiver	ESCI	100710	R&S	2014.10.28	☐
Test Receiver	ESR	101078	R&S	2015.02.24	☒
Bi-Log Antenna	VULB 9168	440	SCHWARZBECK	2015.10.16	☒
Amplifier	310N	293004	SONOMA INSTRUMENT	2014.10.31	☒
3 dB Attenuator	8491B	22981	HP	2015.03.04	☒
Antenna Mast	MA4000-EP	303	Innco Systems	-	☒
Turn Table	DT2000S-1t	079	Innco Systems	-	☒
Amplifier	8449B	3008A02343	AGILENT	2014.10.31	☒
Horn ANT	3115	00155772	ETS	2015.02.26	☒
Spectrum Analyzer	FSP7	100289	R&S	2014.11.25	☐

6.1.4 Sample calculation

The field strength is calculated adding the antenna Factor, cable loss and, Antenna pad adding, subtracting the amplifier gain from the measured reading.

The sample calculation is as follow:

$$\text{Result} = \text{M.R} + \text{C.F}(\text{A.F} + \text{C.L} + 3 \text{ dB Att} - \text{A.G})$$

M.R = Meter Reading

C.F = Correction Factor

A.F = Antenna Factor

C.L = Cable Loss

A.G = Amplifier Gain

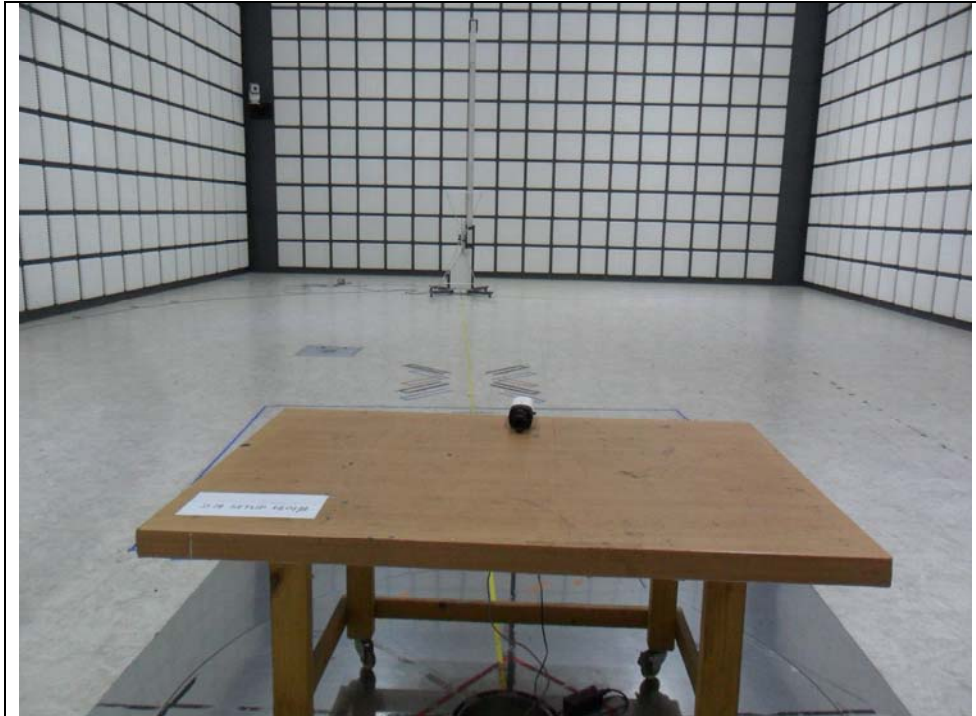
3 dB Att = 3 dB Attenuator

If M.R is 30 dB, A.F 12 dB, C.L 5 dB, 3 dB, A.G 35 dB

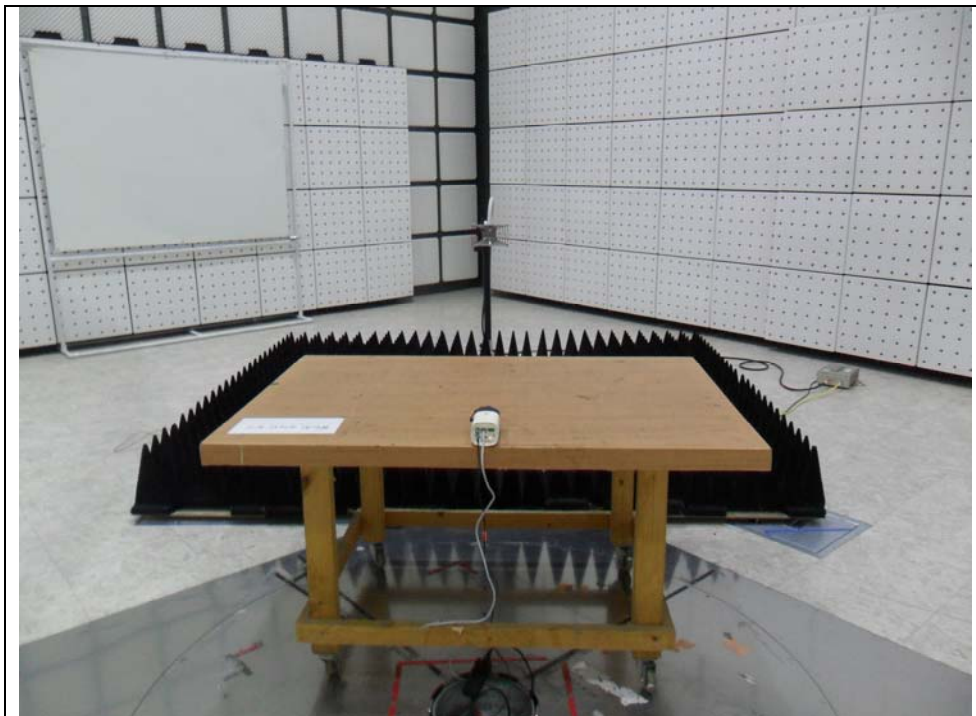
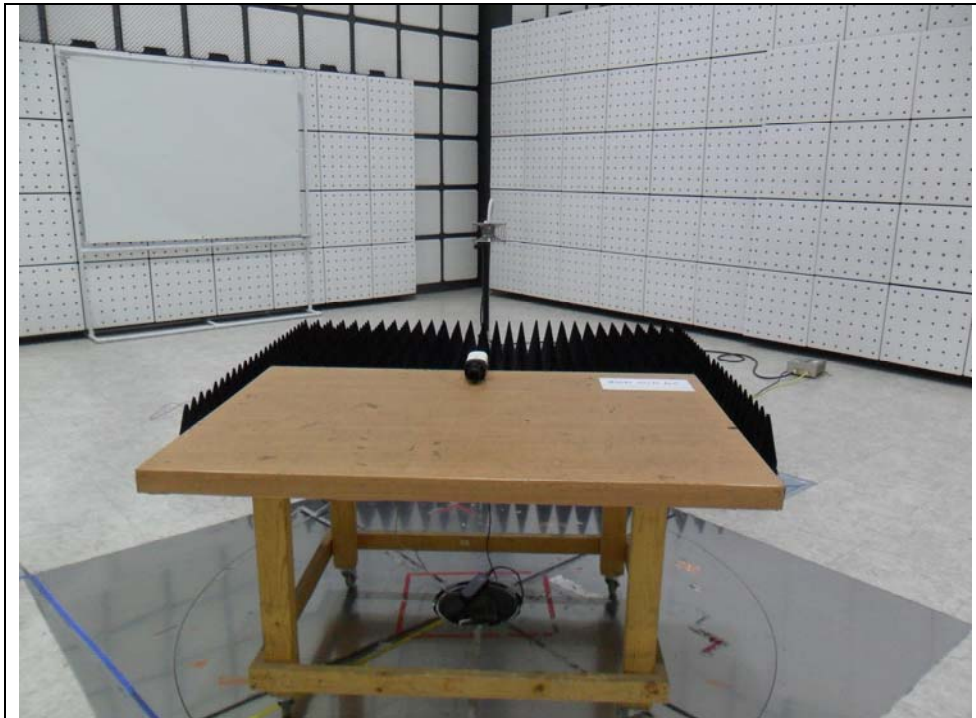
The result is $12 + 5 + 3 - 35 = 15 \text{ dB}(\mu\text{V/m})$

6.1.5 Photographs of test setup

* 30 MHz ~ 1 GHz



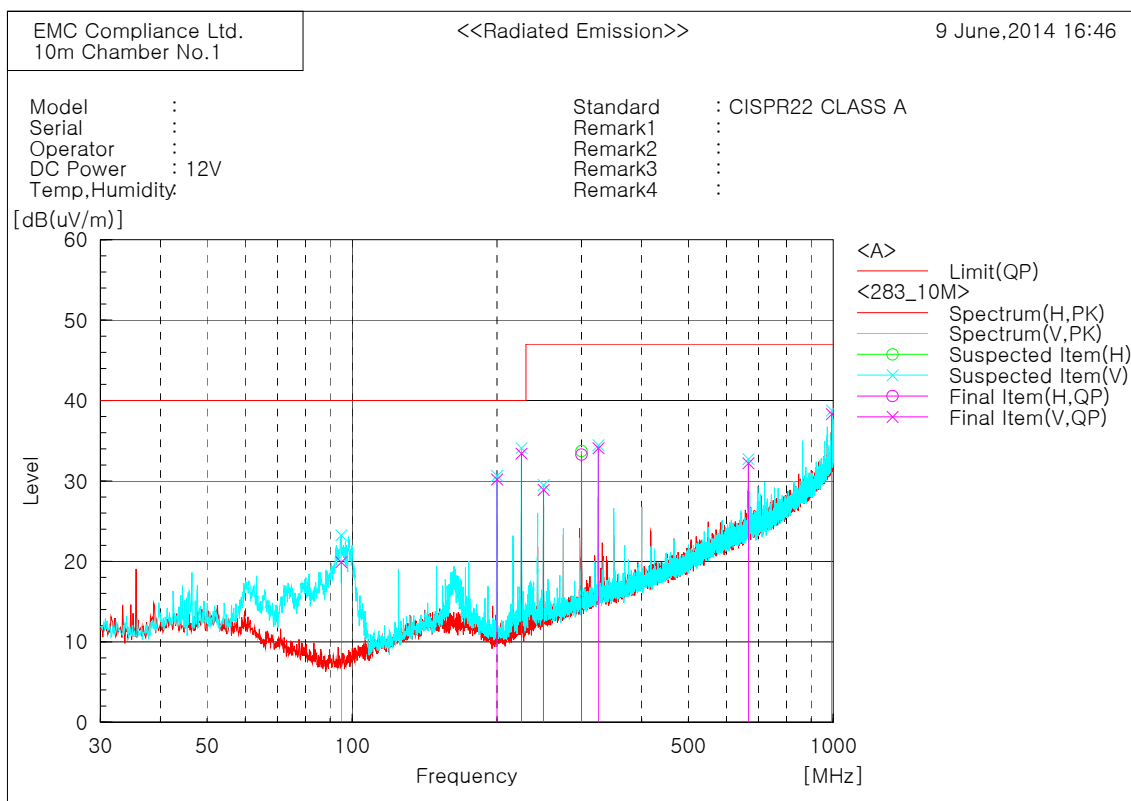
* 1 GHz ~ 6 GHz



6.1.6 Radiated emission measurement result

* Graph and Data

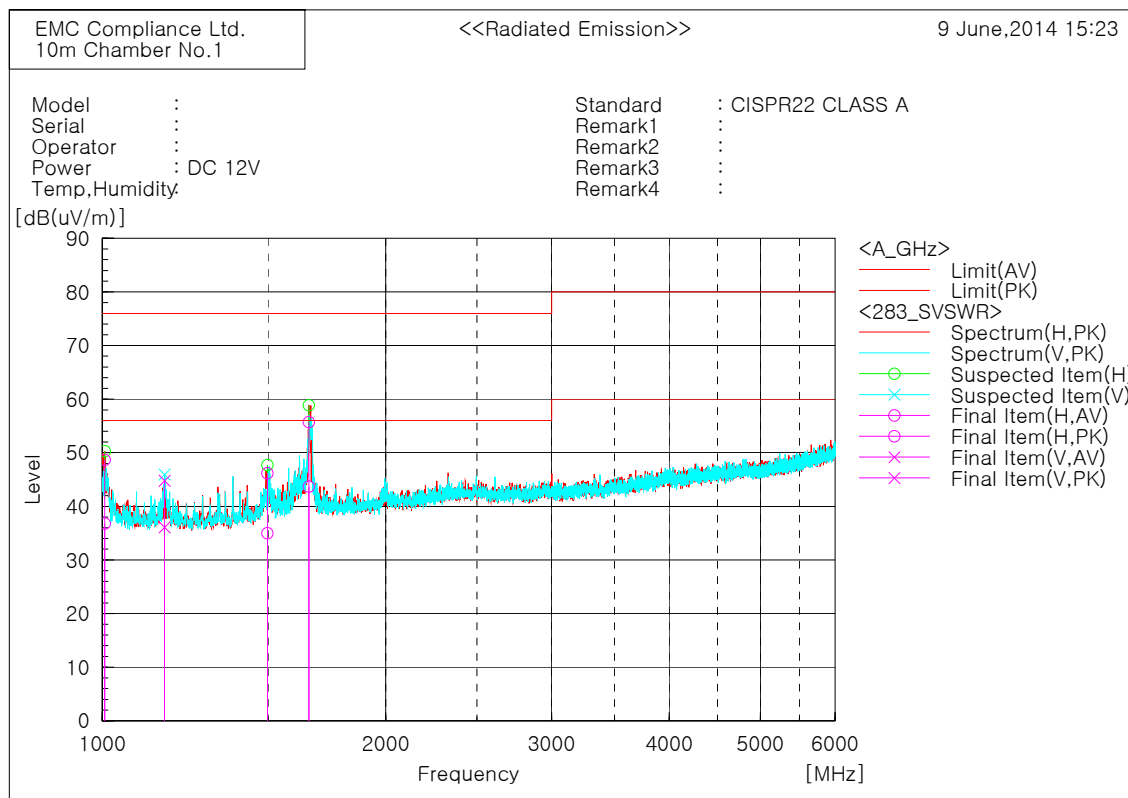
* 30 MHz ~ 1 GHz (SLA-M2890DN)



Final Result

No.	Frequency [MHz]	(P)	Reading QP [dB(uV)]	c.f [dB(1/m)]	Result QP [dB(uV/m)]	Limit QP [dB(uV/m)]	Margin QP [dB]	Height [cm]	Angle [deg]
1	94.990	V	38.1	-18.2	19.9	40.0	20.1	100.0	30.8
2	199.993	V	45.2	-15.0	30.2	40.0	9.8	100.0	155.5
3	224.970	V	47.3	-13.9	33.4	40.0	6.6	100.0	179.4
4	249.947	V	41.2	-12.3	28.9	47.0	18.1	400.0	250.8
5	300.024	H	43.7	-10.4	33.3	47.0	13.7	301.0	7.2
6	325.001	V	43.8	-9.7	34.1	47.0	12.9	100.0	89.5
7	666.078	V	33.3	-1.1	32.2	47.0	14.8	299.0	264.3
8	992.482	V	31.6	6.7	38.3	47.0	8.7	199.0	156.3

* 1 GHz ~ 6 GHz (SLA-M2890DN)



Final Result

No.	Frequency [MHz]	(P)	Reading AV [dB(uV)]	Reading PK [dB(uV)]	c.f [dB(1/m)]	Result AV [dB(uV/m)]	Result PK [dB(uV/m)]	Limit AV [dB(uV/m)]	Limit PK [dB(uV/m)]	Margin AV [dB]	Margin PK [dB]	Height [cm]	Angle [deg]
1	1006.250	H	43.7	55.6	-6.9	36.8	48.7	56.0	76.0	19.2	27.3	100.0	51.5
2	1164.375	V	42.1	50.8	-6.0	36.1	44.8	56.0	76.0	19.9	31.2	100.0	308.0
3	1497.500	H	38.9	50.1	-3.9	35.0	46.2	56.0	76.0	21.0	29.8	100.0	11.4
4	1657.500	H	46.5	58.5	-2.8	43.7	55.7	56.0	76.0	12.3	20.3	100.0	318.2

6.2 Electrostatic Discharge

Test specification	EN 61000-4-2:2009				
Test level	☐ Contact: ± 6 kV ☒ Air: ± 2 kV, ± 4 kV, ± 8 kV ☒ HCP: ± 2 kV, ± 4 kV, ± 6 kV ☒ VCP: ± 2 kV, ± 4 kV, ± 6 kV				
Discharge impedance	330 Ω / 150 pF				
Number of discharge (Each polarity)	☐ Contact: 10 ☒ Air: 10 ☒ HCP / VCP: 10				
Interval between discharges	1 s				
Testing voltage	DC 12 V				
Test facility	Shielded room				
Date	2014. 06. 09				
Temperature(°C)	22.6 °C	Humidity (% R.H.)	46.9 % R.H.	Pressure (kPa)	100.2 kPa
Remarks	Complied - There was no change of operation status during above testing.				

6.2.1 Measurement procedure

A ground reference plane was located on the floor, and connected to earth via a low Impedance connection. The return cable of the ESD generator was connected to the reference plane.

In case of floor standing equipment, EUT was placed on the reference plane on 0.1 m of insulating Support. In case of table top equipment, EUT was placed on a wooden table 0.8 m above the reference grounded floor. A horizontal coupling plane (HCP) was placed on the table, and Connected to the reference plane via a 470 k Ω resistor located in each end (0.5 mm insulating support between EUT and HCP). In both cases a vertical coupling plane(VCP) OF 0.5 X 0.5 m was located 0.1 m from the EUT's sides. The VCP was connected to the reference plane in the same matter as the HCP.

6.2.2 Used equipments

Equipment	Model No.	Serial No.	Makers	Next Cal. Date	Used
ESD Tester	PESD 1600	H011 309	HAEFELY	2014.07.15	☐
ESD Tester	NSG 437	182	TESEQ	2015.04.09	☒
HCP	-	-	-	-	☒
VCP	-	-	-	-	☒

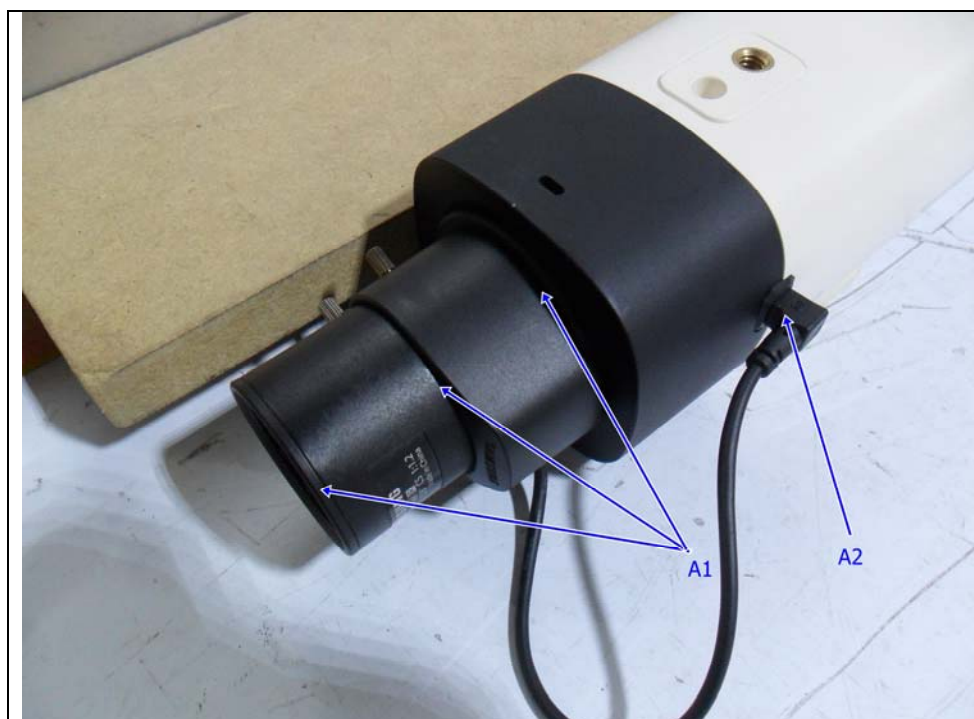
6.2.3 Photographs of test setup



6.2.4 Measurement result

Electrostatic Discharge (Test Point)

Air discharge →
Contact discharge →



HCP/VCP discharge

Location(EUT)	Applied level (±)	Result
HCP (All 4 sides)	± 2 kV, ± 4 kV, ± 6 kV	Complied
VCP (All 4 sides)	± 2 kV, ± 4 kV, ± 6 kV	Complied

Contact discharge

Location(EUT)	Applied level (±)	Result
-	-	-

Air discharge

Location(EUT)		Applied level (±)	Result
A1	Enclosure(Case)	± 2 kV, ± 4 kV, ± 8 kV	Complied
A2	IRIS Port	± 2 kV, ± 4 kV, ± 8 kV	Complied

6.3 Radio Frequency Electromagnetic Fields

Test specification	EN 61000-4-3:2006+A2:2010				
Tested frequency	80 MHz ~ 1 GHz, 1 GHz ~ 2 GHz, 2 GHz ~ 2.7 GHz				
Test level & Modulation	1 V/m, 3 V/m, 10 V/m, 80 % Amplitude Modulation (1 kHz) 1 V/m, 3 V/m, 10 V/m, Pulse Modulation (1 Hz (0.5 s ON: 0.5 s OFF))				
Frequency Step	log 1 % step				
Dwell time	3 s				
Distance	3 m from EUT to tip of antenna				
Testing Voltage	DC 12 V				
Test facility	Fully anechoic chamber (3 m)				
Date	2014. 06. 05				
Temperature(°C)	26.9 °C	Humidity (% R.H.)	32.4 % R.H.	Pressure (kPa)	100.2 kPa
Remarks	Complied - There was no change of operation status during above testing.				

6.3.1 Measurement procedure

The test was performed at 3 m full anechoic chamber.

For floor standing equipment, the EUT was standing on the floor.

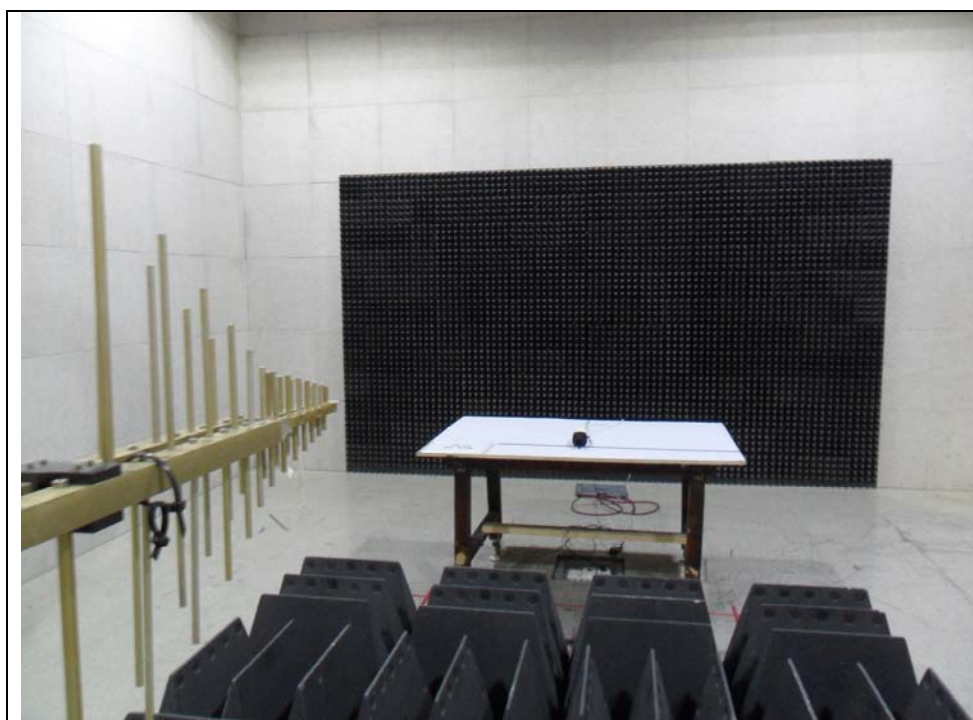
For tabletop equipment, the EUT was located on a wooden table 0.8 m above the floor.

The EUT was tested all sides, horizontal and vertical polarization.

6.3.2 Used equipments

Equipment	Model no.	Serial no.	Makers	Next Cal. date	Used
Power meter	PM2002	302852	AR	2015.02.07	☒
Power sensor	PH2000	303224	AR	2015.02.07	☒
Power sensor	PH2000	311217	AR	2015.02.07	☒
Directional coupler	DC6180	303976	AR	2015.02.06	☒
Directional coupler	DC7144M1	320279	AR	2015.02.06	☒
Signal generator	E4421B	GB40052295	AGILENT	2015.02.06	☒
Broadband Amplifier	BBA100	100996-1	R&S	2015.02.06	☒
Amplifier	60S1G3M2	320444	AR	2015.04.02	☒
Log Periodic Dipole Antenna	LPDA-0803	-	ETS	-	☒
Antenna master	-	-	ETS	-	☒

6.3.3 Photographs of test setup



6.3.4 Measurement result

Location(EUT)	Antenna polarization	Result
Front side	Horizontal	Complied
	Vertical	Complied
Rear side	Horizontal	Complied
	Vertical	Complied
Left side	Horizontal	Complied
	Vertical	Complied
Right side	Horizontal	Complied
	Vertical	Complied

7. E.U.T. photographs

Front View



Rear View



Left View



Right View



Top View



Bottom View

